

**Search Notes**

Application/Control No.

10/662,382

Examiner

Chris C. Chu

Applicant(s)/Patent under  
Reexamination

KANAI ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	E23.079, E23.171, 700 & 737	12/4/2006	C.C.
257	776 - 781	12/4/2006	C.C.
257	773 & 774	12/4/2006	C.C.
257	758 & 688	12/4/2006	C.C.
257	690 & 692	12/4/2006	C.C.
438	108 & 113	12/4/2006	C.C.
438	123 & 612	12/4/2006	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
As same	as above	12/4/2006	C.C.

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	12/4/2006	C.C.